

RECENT PROGRESS AND EMERGING TECHNOLOGIES OF SPINTRONICS DEVICE FOR VLSI

- 1- Spintronics basics
- 2- MRAM
- 3- Logic-In-Memory
- 4- Emerging concepts

MAGNETISM BASICS

Electrons have a charge and a spin

Orbital moment + Spin moment + Spin-Orbit



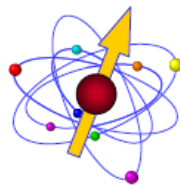
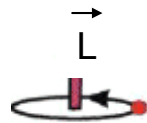
Spin moment



$$\vec{S} = +1/2 \text{ or } -1/2$$



Atomic Moment

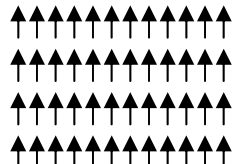


$$\vec{J} = \vec{L} + \vec{S}$$

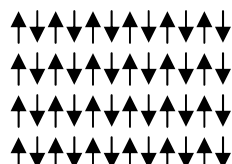
Exchange Interactions
 $-J_{\text{ex}} \vec{S}_i \cdot \vec{S}_j$



Macroscopic Magnetization



Ferromagnetic

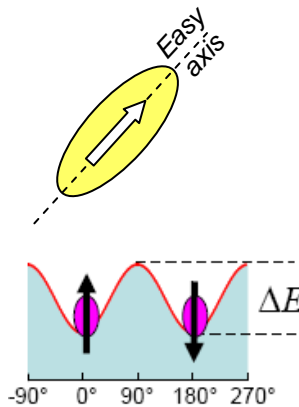


Antiferromagnetic

Lattice coupling + shape anisotropy



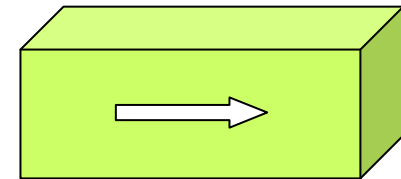
Magnetic anisotropy



$$\Delta E = K_u V$$



Permanent magnet

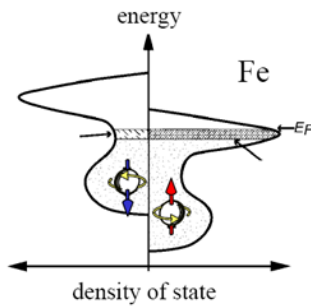


- Intrinsic logic system (2 states)
- Non volatile
- Size-independent

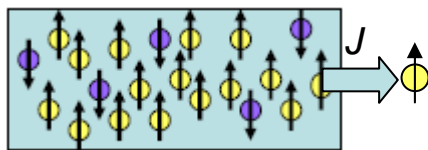
... as long as $\Delta E > k_B T$

SPIN TRANSPORT

Exchange interaction
→ Band splitting

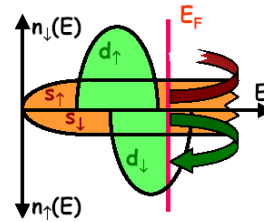


Spin polarized current in
and exiting magnetic layers

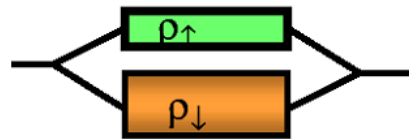


Sustained until spin-flipping
diffusion event

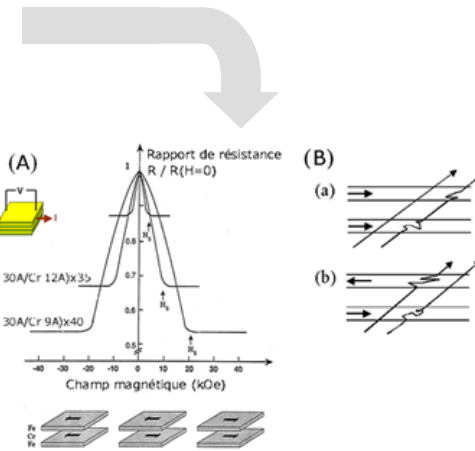
In metals, if spin flip marginal
→ Scattering proportional to
available DOS just above E_F



Mobility (conductance)
asymmetry



ρ depends on relative orientation
of spin current and local \vec{M}



Giant MagnetoResistance (GMR)

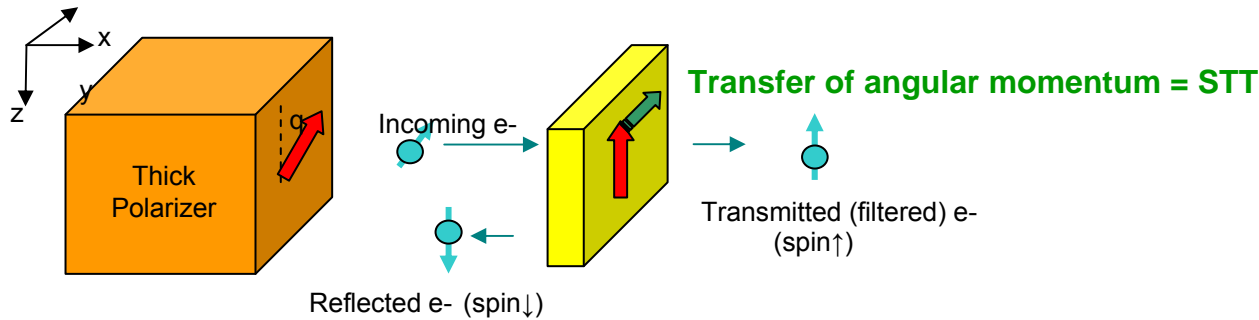
2007
Nobel Prize



Dr. Grunberg Prof. Fert

SPIN TRANSFER TORQUE (STT)

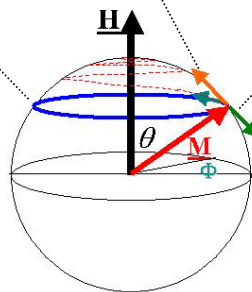
Magnetization → (Resistance) → Current ⇒ « Magnetoresistance »
 (Spin) Current → Magnetization ⇒ « Spin Transfer Torque »



Extended Gilbert equation :

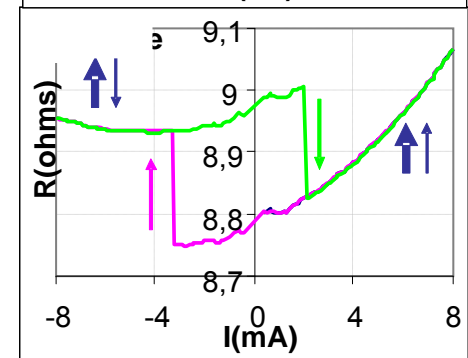
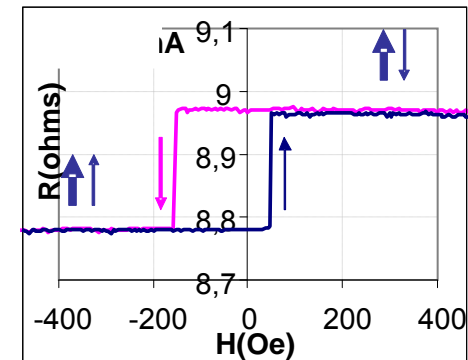
$$\frac{d\vec{M}}{dt} = \underbrace{-\gamma(\vec{M} \times \vec{H}_{eff})}_{\text{Precession}} + \underbrace{\frac{\alpha}{M_S} \vec{M} \times \frac{d\vec{M}}{dt}}_{\text{Damping}} + \underbrace{\frac{\gamma a_J(\theta)}{M_S} \vec{M} \times (\vec{M} \times \vec{P})}_{\text{Spin torque (ST)}} - \frac{\gamma b_J(\theta)}{M_S} (\vec{M} \times \vec{P})$$

Precession Damping Spin torque (ST)

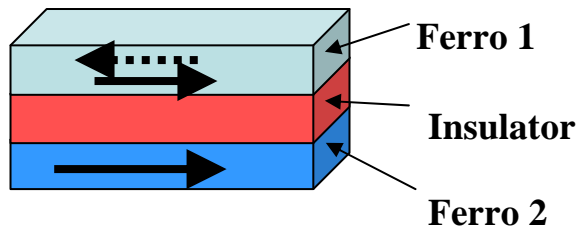


If spin torque < damping torque
 → No switching

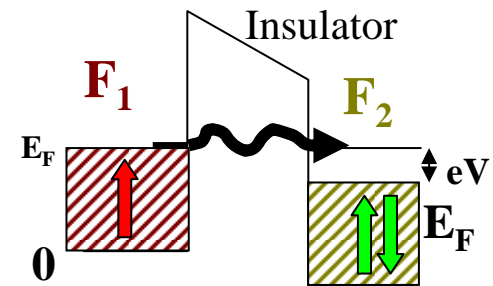
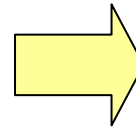
If spin torque > damping torque
 → Switching



SPINTRONICS BUILDING BLOCK : THE MTJ

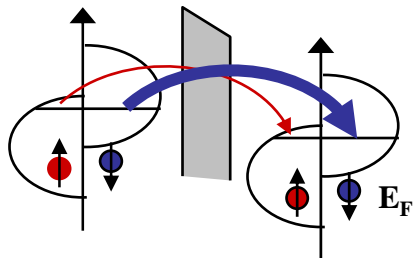


Magnetic Tunnel Junction



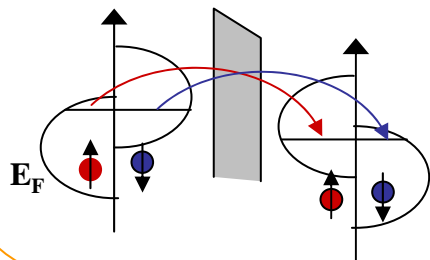
$$\sigma \propto n_1(E_F) \times n_2(E_F)$$

Parallel state

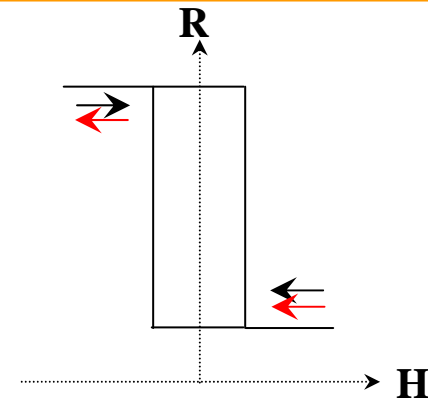
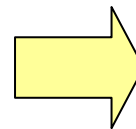


Low R

Antiparallel state



High R

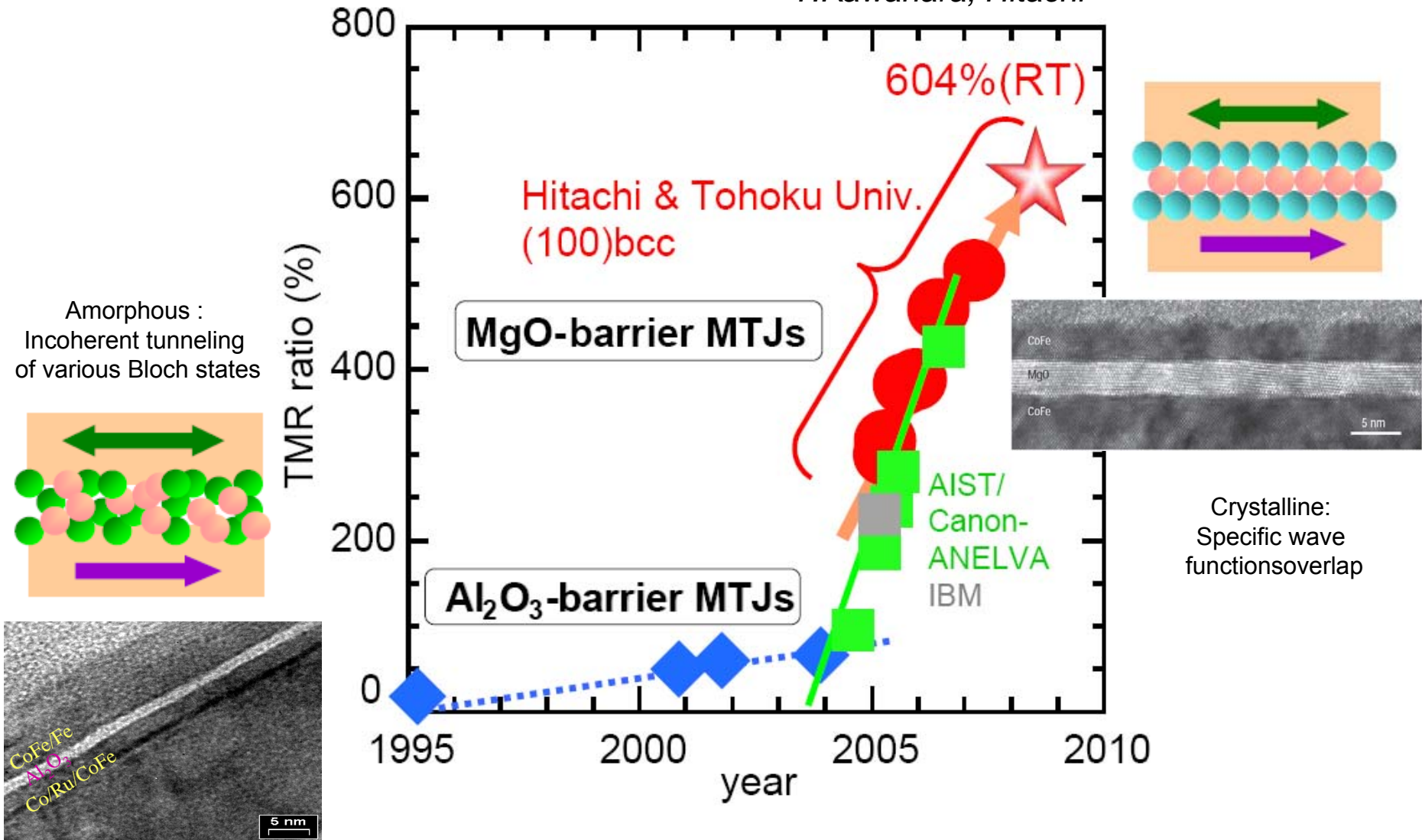


$$TMR = \frac{R_{\uparrow\downarrow} - R_{\uparrow\uparrow}}{R_{\uparrow\uparrow}}$$

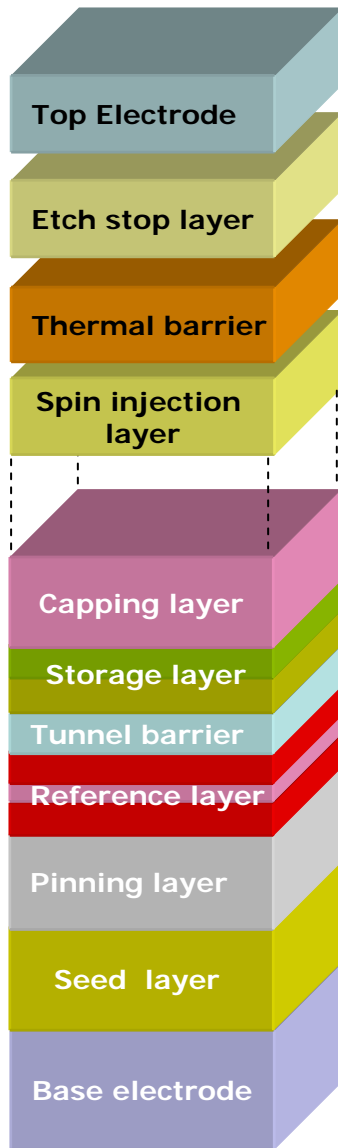
Tunnel Magneto-Resistance

MRAM BUILDING BLOCK : THE MTJ

T.Kawahara, Hitachi

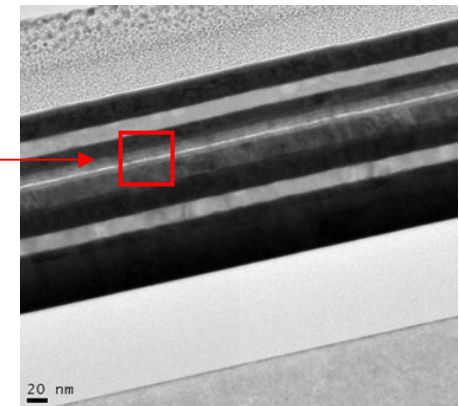


MRAM BUILDING BLOCK : THE MTJ



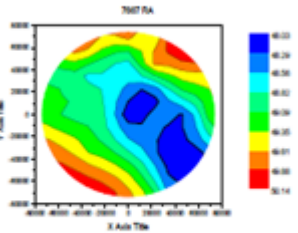
Complex but mastered for volume manufacturing
(1 millions heads/day since 5+ years !)

- *Protects MTJ during process*
- *NiFe(3) / CoFe(2) : Stores data (2 stable states)*
- *MgO (1.1) : Defines cell R & TMR*
- *CoFeB(2) / Ru(0.8)/CoFe(2) : SAF, immune to external fields*
- *PtMn(20) : AF layer sets direction of reference layer*
- *Ta(5) or NiFeCr(10) : Promotes texture of critical layers*
- *Contact to select transistor + diffusion barrier*



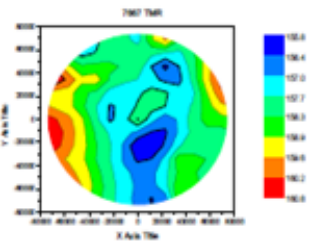
MTJ MANUFACTURING

RA

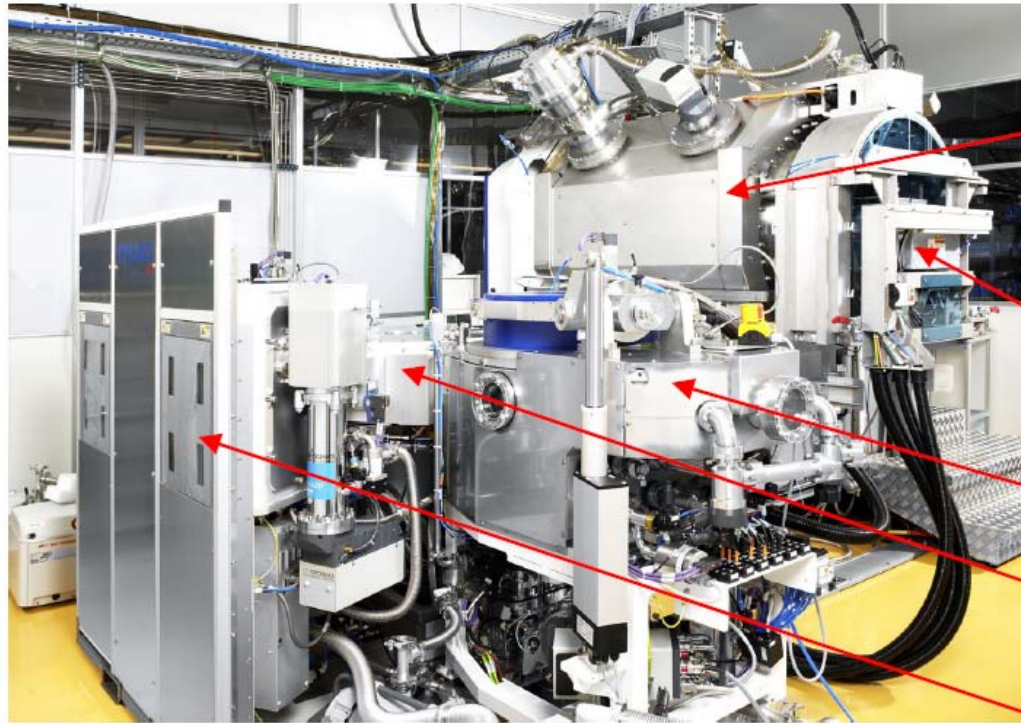


49.1 Ohm μm^2
1.3% (1sigma)

LINEA



158.2%
1.0% (1sigma)



Multi Target Module

Top: Target Drum with 10 rectangular cathodes; Drum design ensures easy maintenance;

Bottom: Main part of the chamber containing LDD equipment

RF - Equipment

(Match - Box, RF - Switches)

Soft-Etch Module

(PreClean, Surface Treatment)

Transport Module

(UHV wafer handler MX700)

Cassette Modules

(according to Customer request)

Ultra - High - Vacuum Design: Base Pressure $\leq 5 \cdot 10^{-9}$ Torr (Deposition Chamber)

High Throughput: ≈ 10 Wafer/Hour (NiFe 2.5nm/CoFe70 250nm)

High Tool Availability: Maintenance friendly Design

High Reliability: Solid and Well Engineered Design \rightarrow Up-Time: $\approx 90\%$, MTBF: $\approx 150\text{h}$, MTTR: $\approx 3\text{h}$

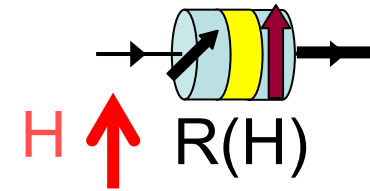


SINGULUS
NANO DEPOSITION TECHNOLOGIES

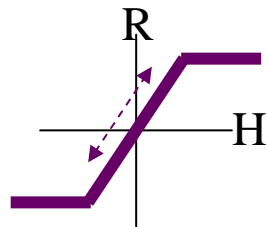
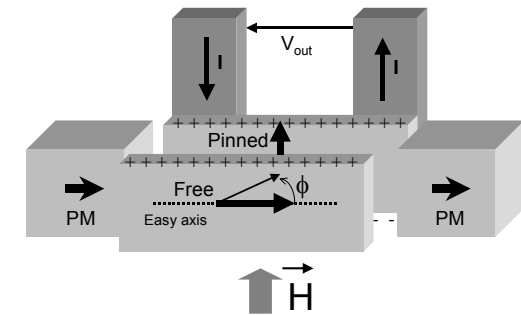


GMR/TMR SENSORS

External Field \rightarrow Magnetization \rightarrow Resistance

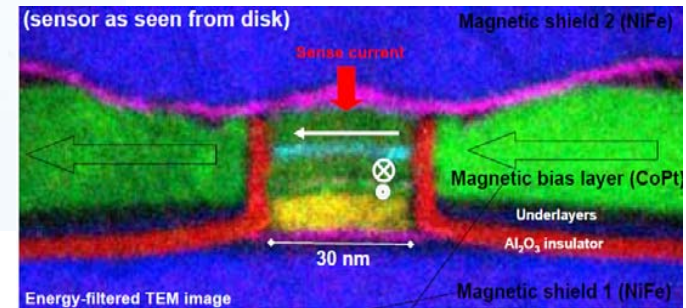
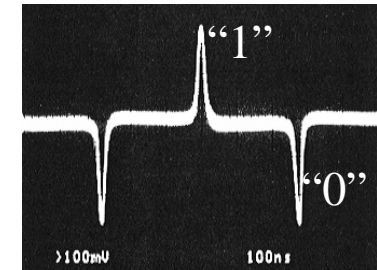
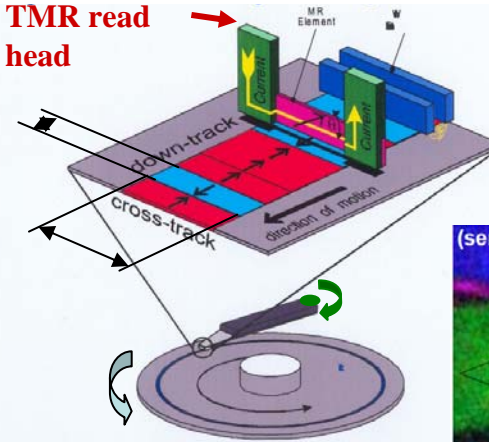


Position sensors
(earth field)



Disk drive heads
(media bits stray field)

TMR read head



Peripheral (CMOS) circuit not integrated
Single element devices
Volume manufacturing on Si or AlTiC wafers
Sub-“30nm” technology

MAGNETIC RANDOM ACCESS MEMORIES

Magnetization state \rightarrow Logic memory state

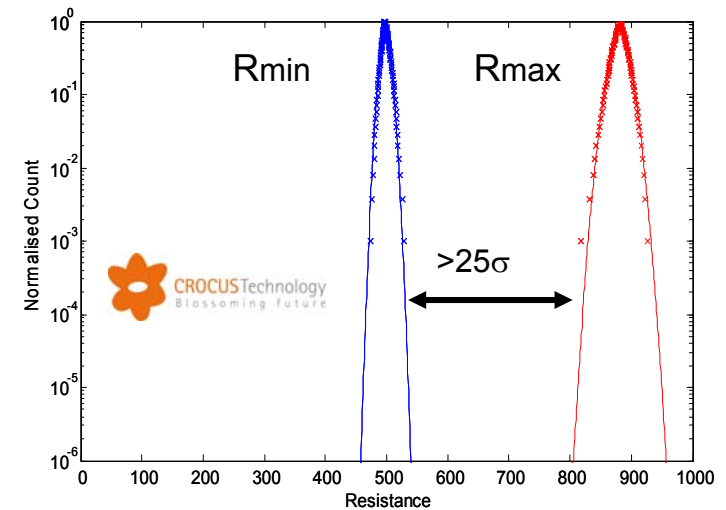
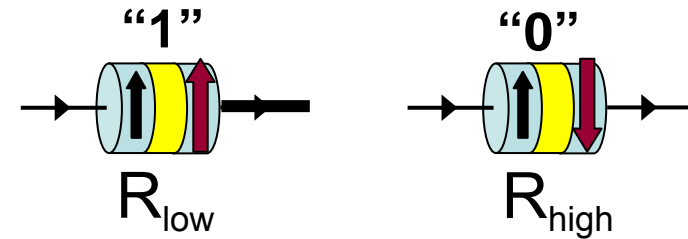
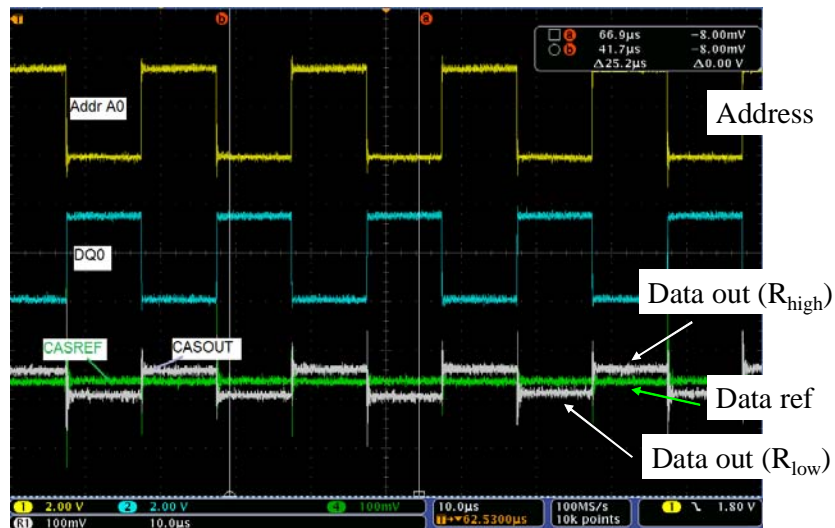
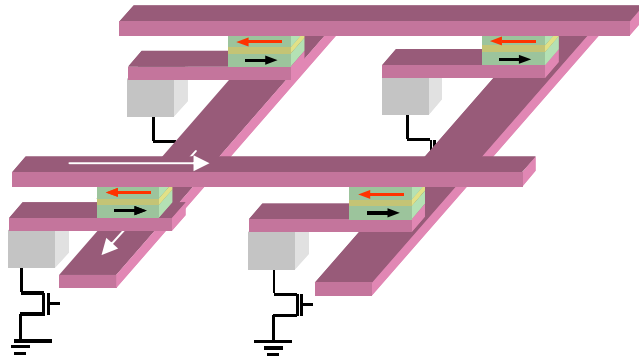
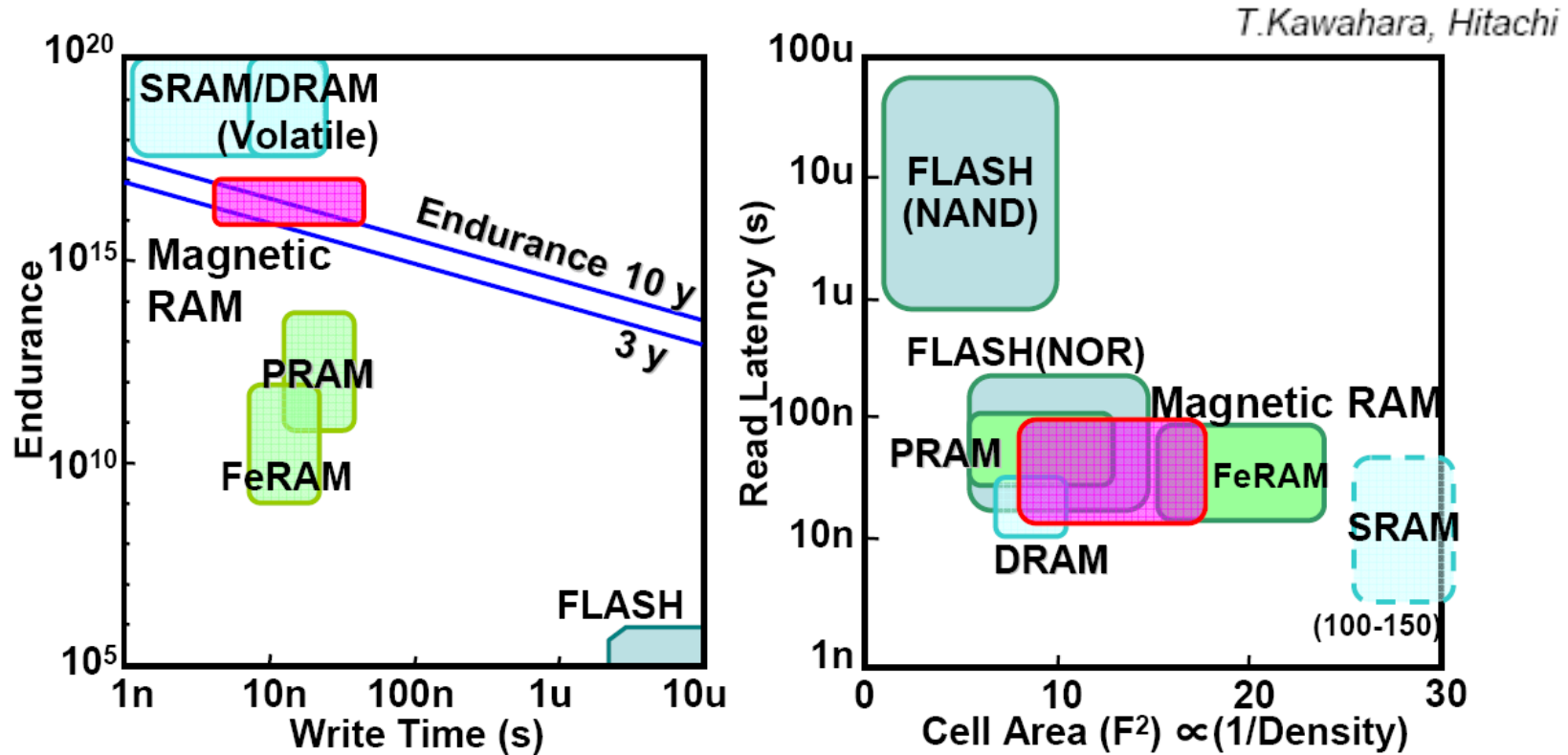


Figure of merit is not ΔR , but $\Delta R/\sigma$
 $\Delta R/\sigma > 25$ for functional device,
 > 40 for production-worthy process
 WW distribution 1σ need to be $< 1\%$

WHY MRAM ?

Although not the best in each category, MRAM is the only memory which scores everywhere

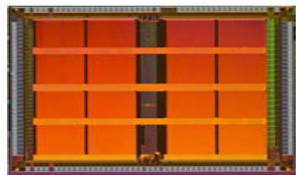
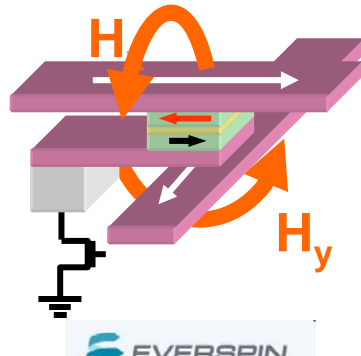


Fast, non-volatile, infinite endurance memory

+ moderate power (no HV), rad-hard, easy to embedd

THERE ARE MANY MRAM !

Field-only « Toggle »

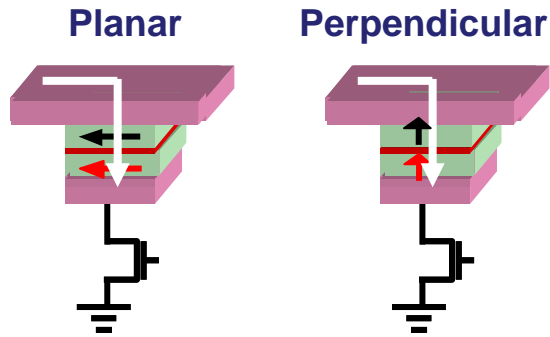


Freescale 4Mb (2006)

Established technology
1.5M units shipped
4.5M forecasted in 2011
Infinite endurance

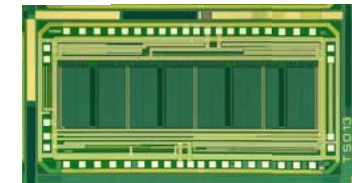
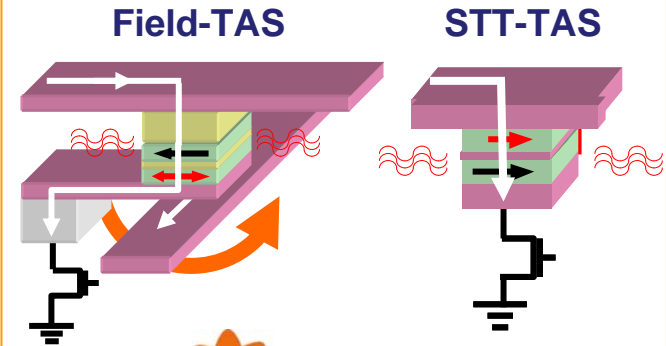
Scalability beyond 90 nm ?
(Write power increase)

Spin Transfer Torque « STT » or « SPRAM »



Lowest write current
($<100\mu\text{A}$, scales with shrink)
Minimal cell / array size
($\sim 15\text{F}^2$, soon not Xtor limited)
Low sensitivity to field disturb
Beware of stability
(retention at small feature)

Thermal Assist « TAS » or « TAMRAM »



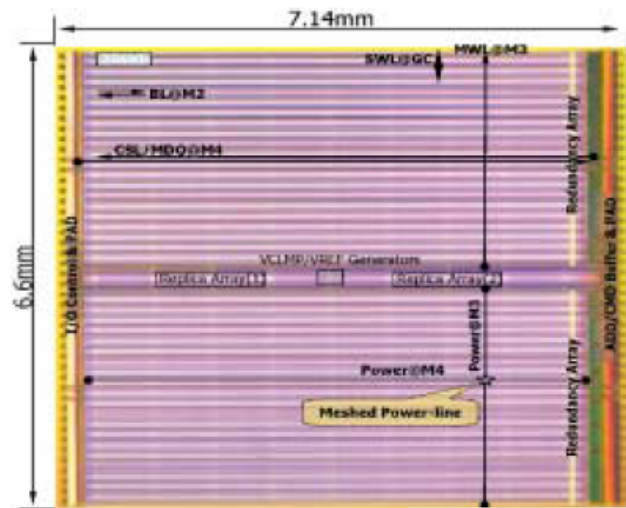
1Mb Field-TAS (2011)

Fully scalable
(stability / retention to $<20\text{nm}$)
Multibit possible
Limited array efficiency
(+ large field drivers)

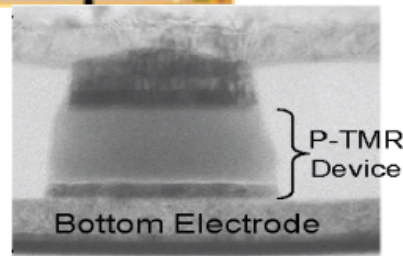
Combine both !

Perpendicular TMR (Toshiba)

- Process: **65 nm**
- Power Supply: **1.2 V**
- Density: **64 Mb**
- Chip size: **47.12 mm²**
- Cell size: **0.3584 μm² (84.8F²)**
- Write Current: **50 uA**
- TMR device: **Perpendicular**

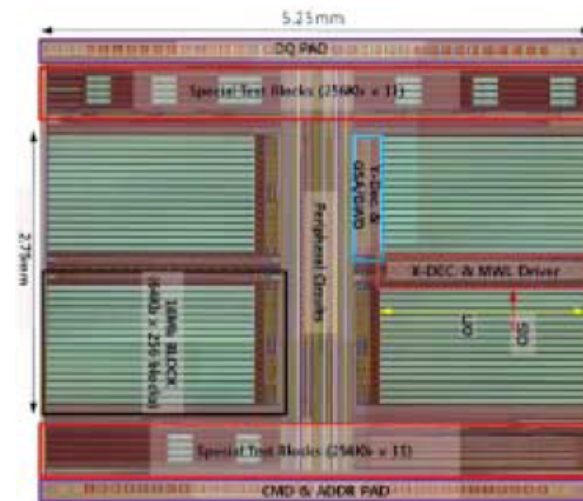


K. Tsuchida, et al.,
ISSCC 2010

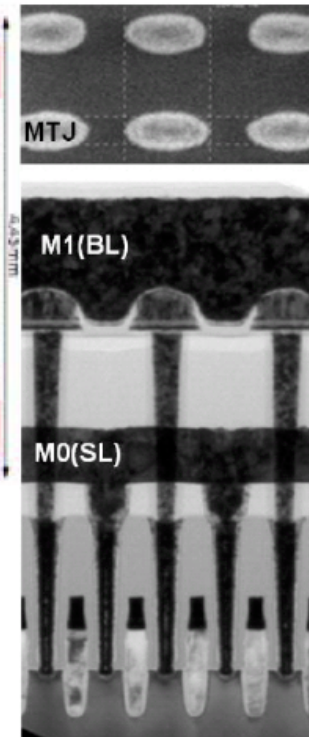


Modified DRAM Process (Hynix, Grandis)

- Process: **54 nm**
- Power Supply: **1.8 V**
- Density: **64 Mb**
- Chip size: **23.36 mm²**
- Cell size: **0.041 μm² (14F²)**
- Write Current: **140 uA**
- TMR device: **In-plane**

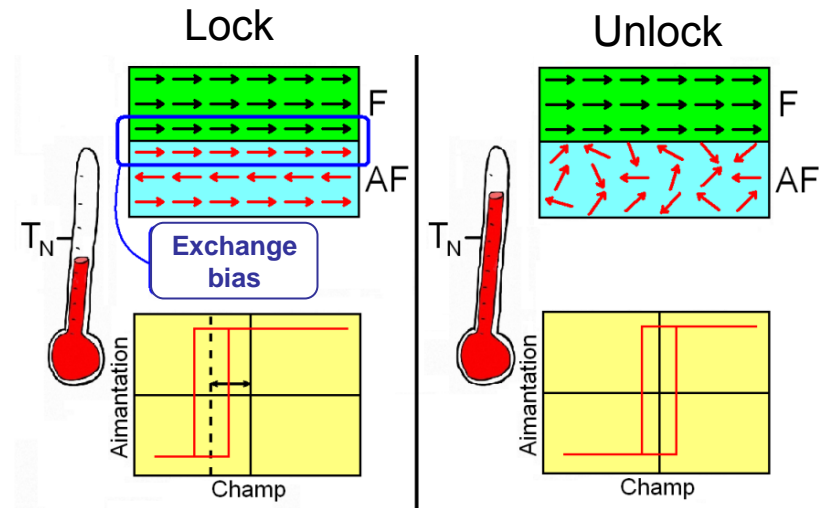


S. Chung, et al.,
IEDM 2010

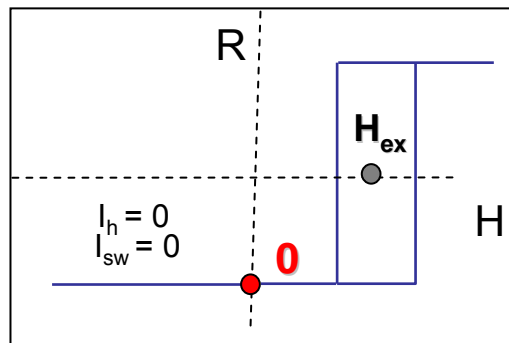


TAS MRAM PRINCIPLE

- ❖ Use **exchange biased bilayer** to “lock” the stored data (**high stability**)
- ❖ **Heat the cell** above to “unlock” the data
- ❖ Analogous to Heat Assisted Recording in HDD (write at elevated T, store at RT)

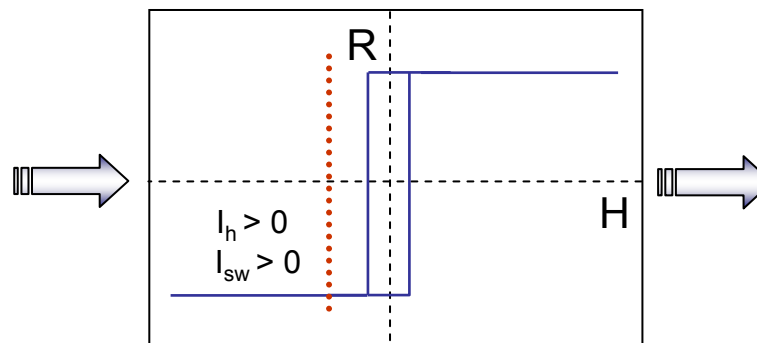


TAS write sequence



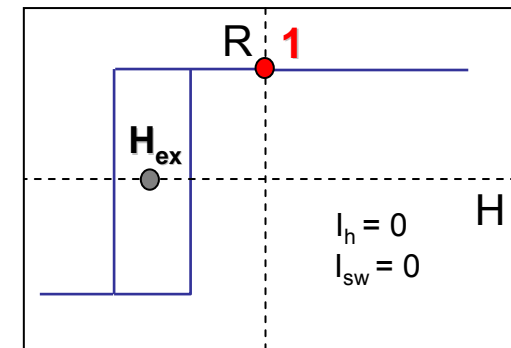
T = ambient temperature

Step 1: Heat cell by flowing current through transistor



T > blocking temperature

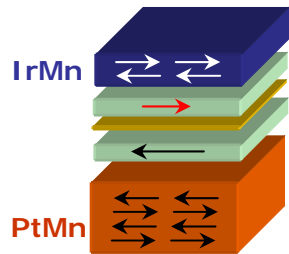
Step 2: Switch magnetization by a **magnetic field or STT** torque



T = ambient temperature

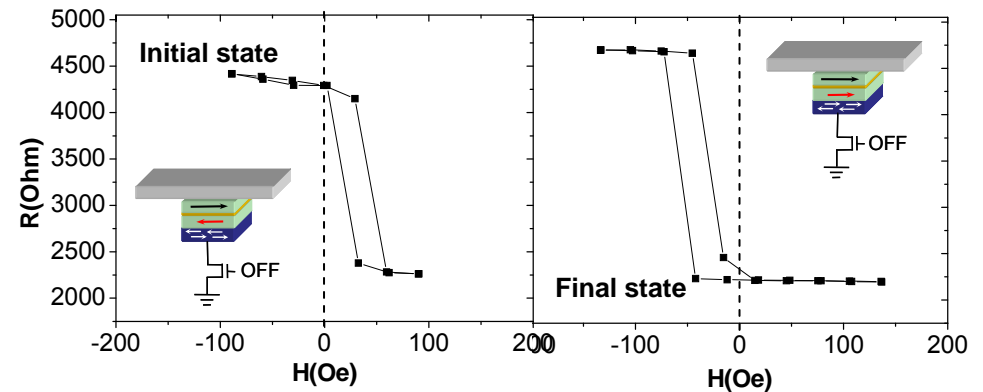
Step 3: Cool under magnetic field or STT torque

STT + TAS PROOF OF CONCEPT

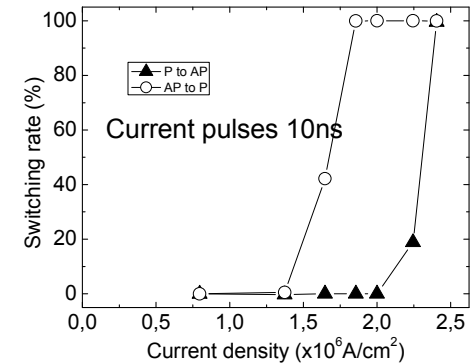
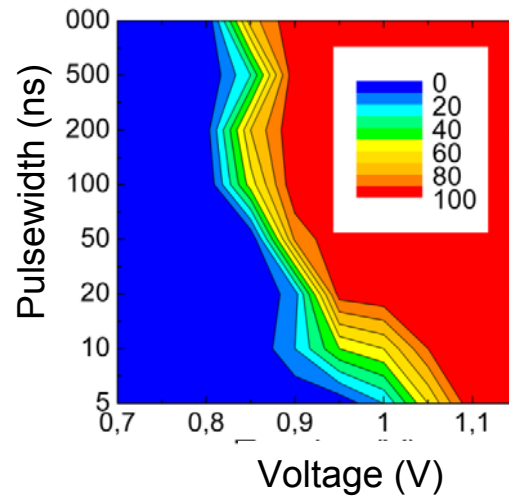
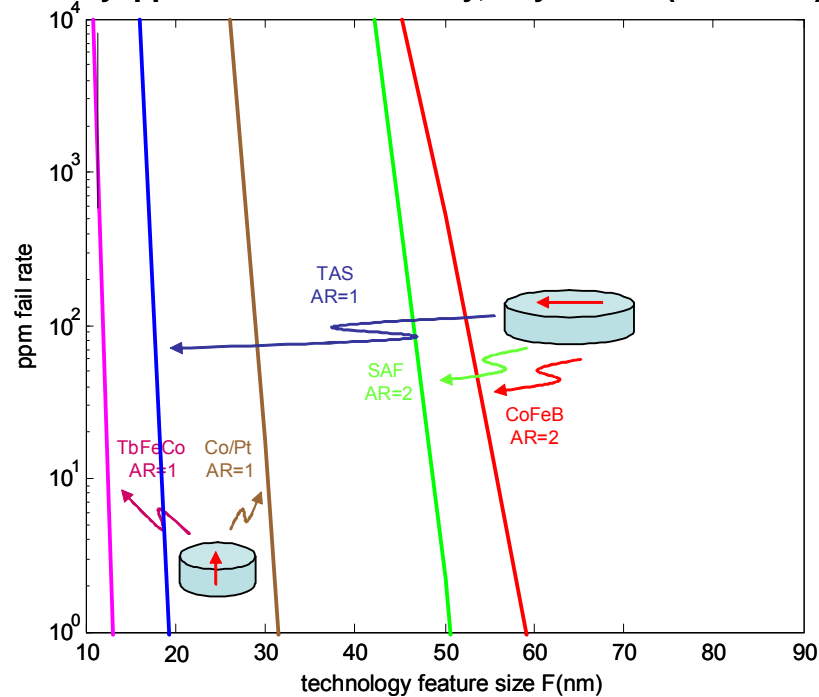


TAS-Field MTJ stack

- ❖ RxA from $30\Omega\mu\text{m}^2$ to $10\Omega\mu\text{m}^2$
- ❖ TMR up to 130%
- ❖ Cell size 50nm (circular)



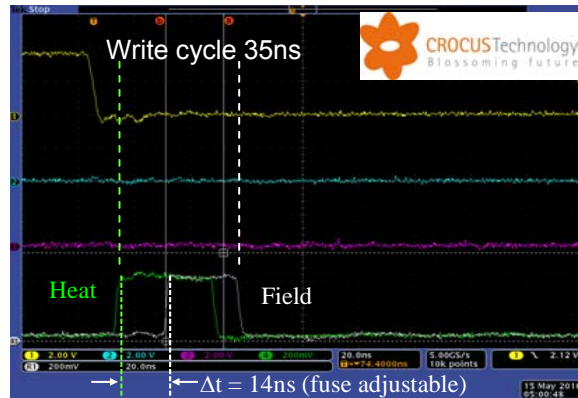
10yr ppm fail rate in 32M array, 10 years life (calculated)



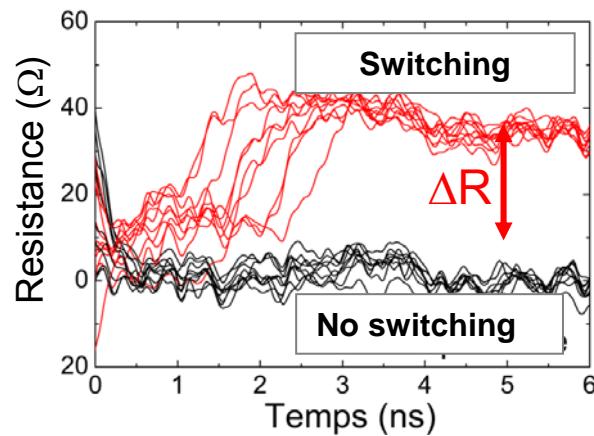
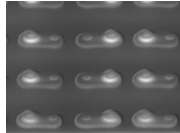
- ❖ Current density @ 10ns $J_c = 2.4 \cdot 10^6 \text{ A/cm}^2$
- ❖ $KV/k_B T > 100$ at 32nm feature size (AR=1)

HOW FAST CAN MRAM BE ?

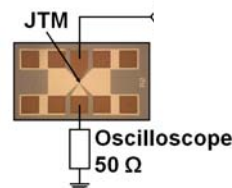
Field MRAM



Chip level

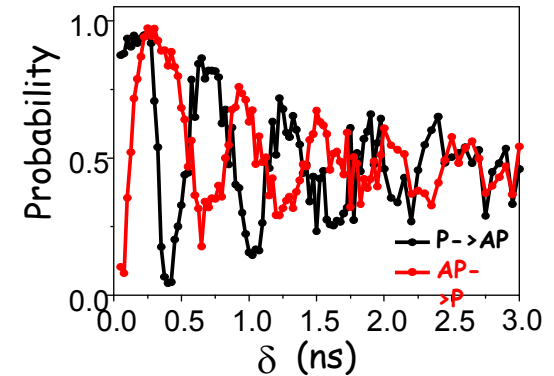
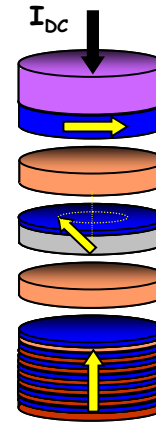


Real-time dynamic test

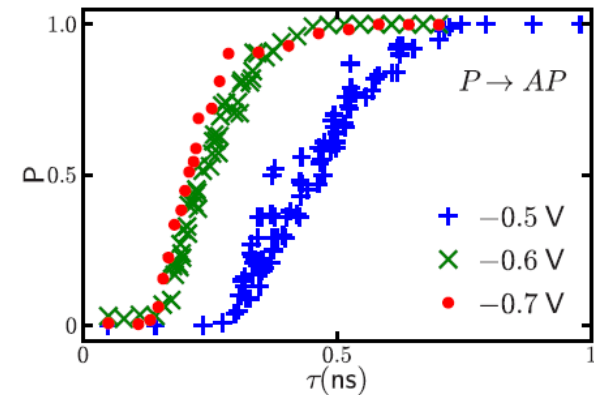


Switching transient $\sim 1\text{ ns}$
Switching time 5-10 ns (thermally activated)
Product Write cycle $\sim 30\text{ ns}$

STT Precessional switching



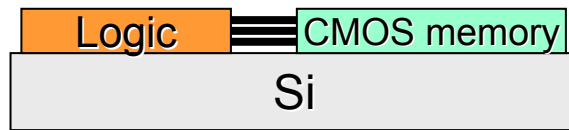
H.Liu et al, APL97, 242510 (2010)



Switching transient $\sim 200\text{ ps}$
Switching time $< 1\text{ ns}$ (deterministic)
Expected Write cycle $\sim 2\text{-}3\text{ ns}$

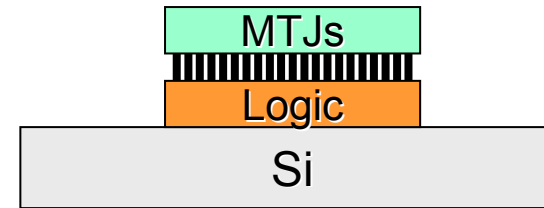
(MAGNETIC) LOGIC-IN-MEMORY

Von Neuman SoC



Large Si footprint, long interconnects
→ Delay, capacitive loss, complex layout, heat

“Janus” SoC

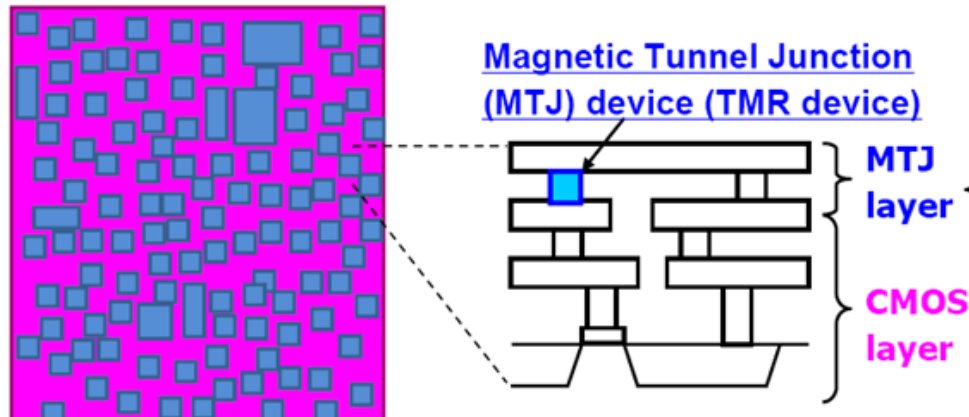


Minimal Si footprint, short interconnects
→ Faster, simpler layout, reduced dynamic power

Logic-in-memory concept (introduced in 1969)

Storage elements are distributed over the logic plane

Non volatility directly inside the logic circuit



Non volatile memory
→ No leakage
→ **Static power off**
Reduced wire count
→ **Minimal dynamic power, delay**
Optimal layout

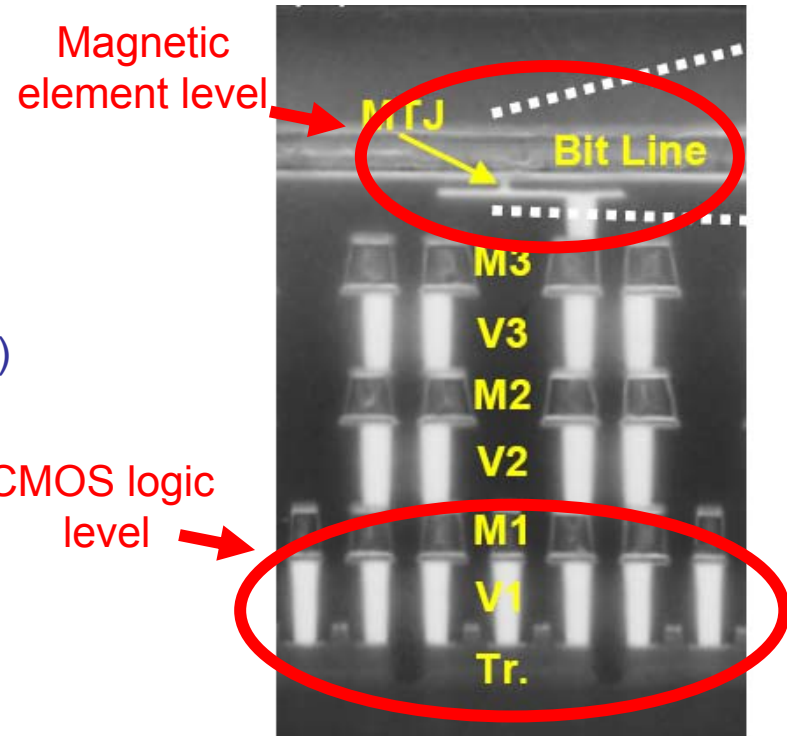
Need NV, fast, infinite endurance, CMOS compatible memory !

MTJ-BASED LOGIC CIRCUITS

- Infinite endurance ($>10^{16}$ for field write)
High speed (1-30ns)
- Cell R adjustable, from Ω 's to $M\Omega$'s
→ Match with CMOS ($\sim k\Omega$)
- Cell is variable resistance driven by low voltage
→ use as standard library IP
- Can be deposited on any substrate
→ "end-of-back-end" process (above-IC)
no impact on logic process
only 3 add-masks

Front-end contamination under control
Low-T BE process (250°C) compatible with Cu
interconnect process

Etch still « tricky » → IBE vs. RIE ?

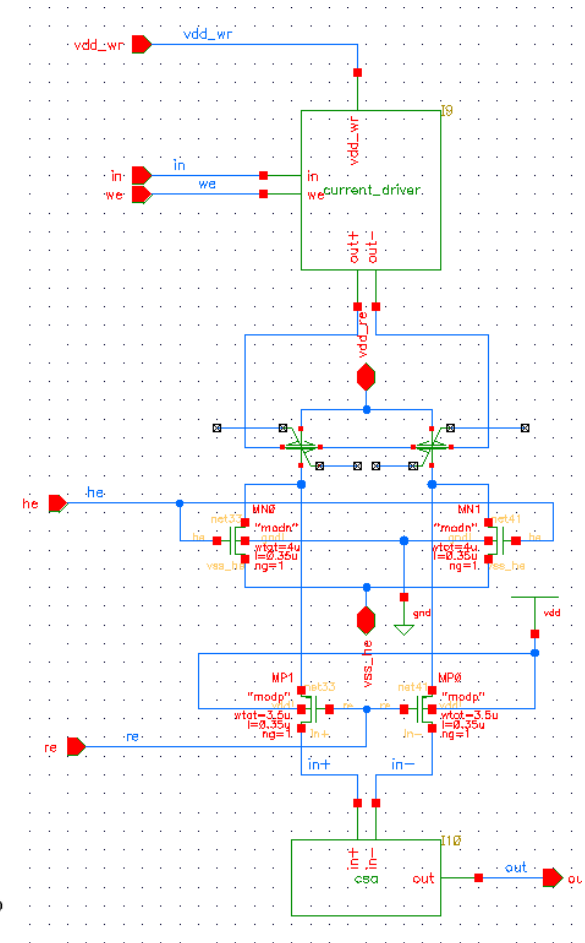
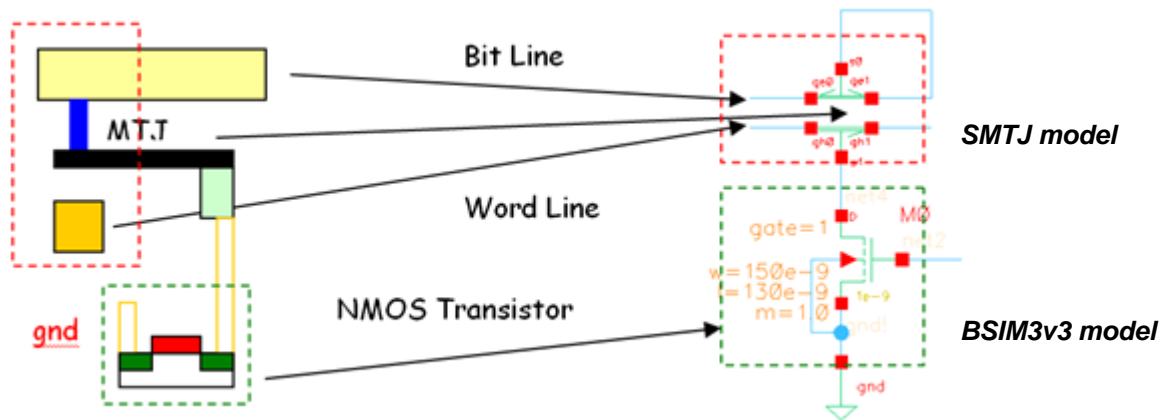


MRAM process well established
Fear for contamination (slowly) vanishing
Several fabs now enabled with 200/300mm lines

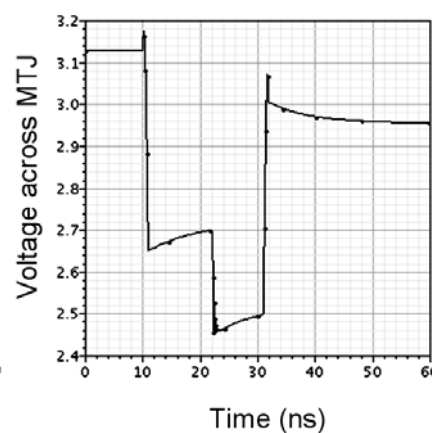
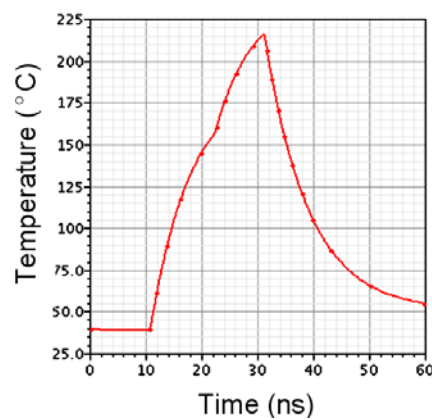
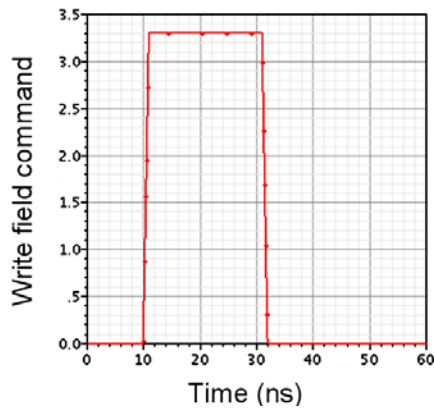


MTJ ELECTRICAL COMPACT MODEL

High-Speed compact model → Electrical behavior of MTJ written by field, STT and with/without thermal assistance.
SPECTRE (5.0) compatible (CADENCE platform analog solver).



Simulation of a TAS-MRAM



(MAGNETIC) NV-LOGIC CIRCUITS

Hitachi + Tohoku University

S.Matsunaga et al, *Applied Physics Express*, vol. 1, 2008.

- NV-Full Adder
 - One input is made non-volatile (instant startup, security)
 - Drastic static consumption reduction
 - Footprint reduction
- Demonstrator : CMOS 0.18 μ m,
- MTJs size: 200X100nm²

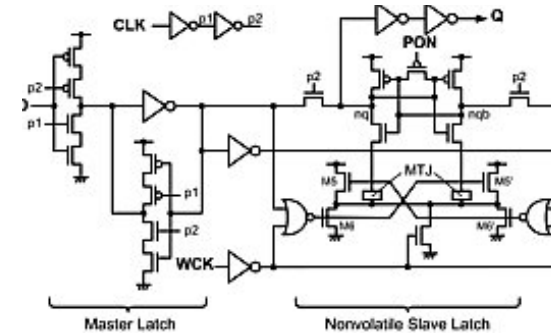
	CMOS	Hybrid
Delay	224 ps	219 ps
Dynamic Power	71.1 μ W	16.3 μ W
Writing Time	2 ns/bit	10 (2) ns/bit
Writing Energy	4 pJ/bit	20.9 (6.8) pJ/bit
Standby Power	0,9 nW	0 nW
Surface	333 μ m ²	315 μ m ²

NEC Empowered by Innovation

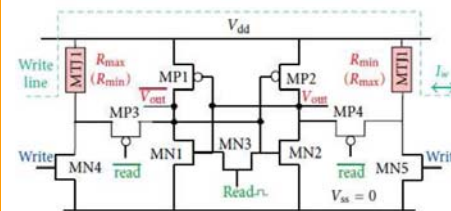
Home

Home > News Room > NEC develops a nonvolatile magnetic flip flop that enables standby-power-free SoCs

NEC develops a nonvolatile magnetic flip flop that enables standby-power-free SoCs

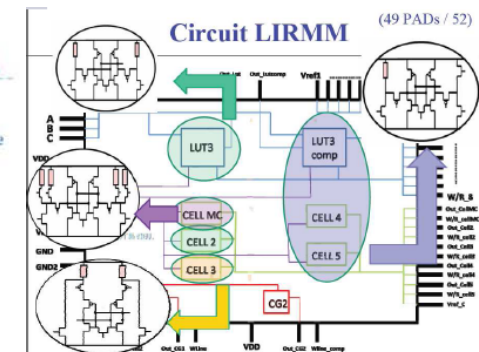


R-SRAM ©



Magnetic Flip-flop

Magnetic LUT



REPROGRAMMABLE (MAGNETIC) LOGIC



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Press Releases

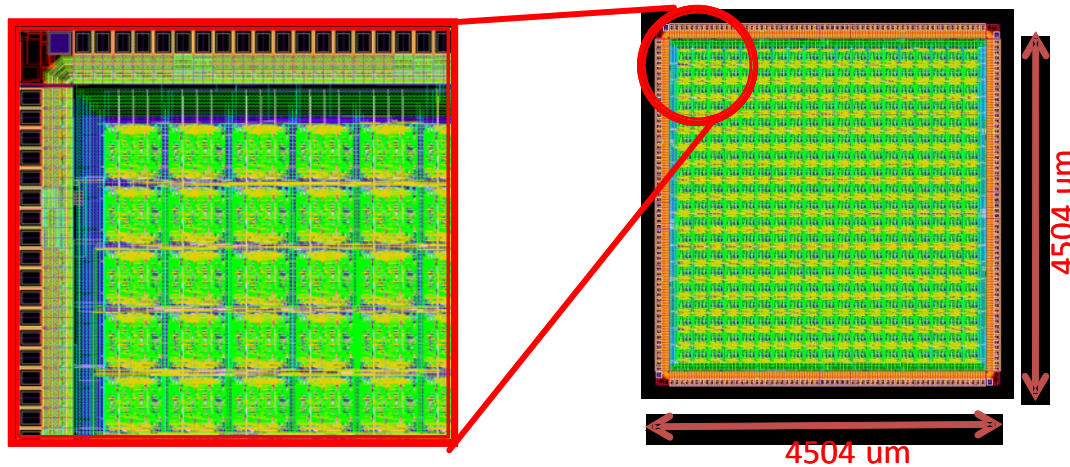
09-06-10 08:39

Menta and LIRMM Launch Manufacturing of World's First MRAM-based FPGA

MONTPELLIER, France, June 9, 2010 — Menta SAS and LIRMM, an embedded programmable logic provider of embedded-FPGA Intellectual Property (IP) and a joint CNRS and University of Montpellier 2 research laboratory, today confirmed the tape out of world's first MRAM-based FPGA. The MRAM-based FPGA leverages key innovations including non-volatile magnetic memory and patent-protected circuitry enabling compact integration of MRAM and embedded-FPGA solutions.

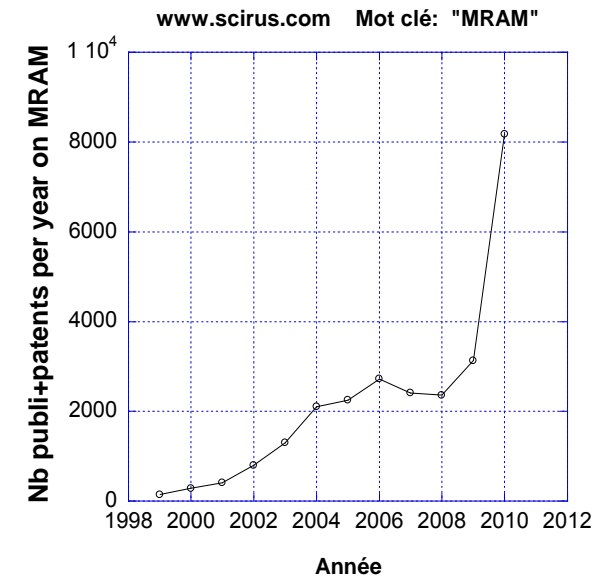
# LUT 4	1444
# TILES	361 (19x19)
# Sequential elements	1444
# of MTJs	187 720
# of Transistors	9. 10 ⁶
Silicon Area	21mm ²
MRAM Reconfiguration Tile Energy	9 nJ
MRAM Restoration Tile Energy	25,5 pJ
Clock Frequency	100 MHz
Full configuration time	72us + 93K Clock cycles
Tile reconfiguration	200ns + 260 Clock cycles
# Input/Output	76 Input / 76 Output

mtile

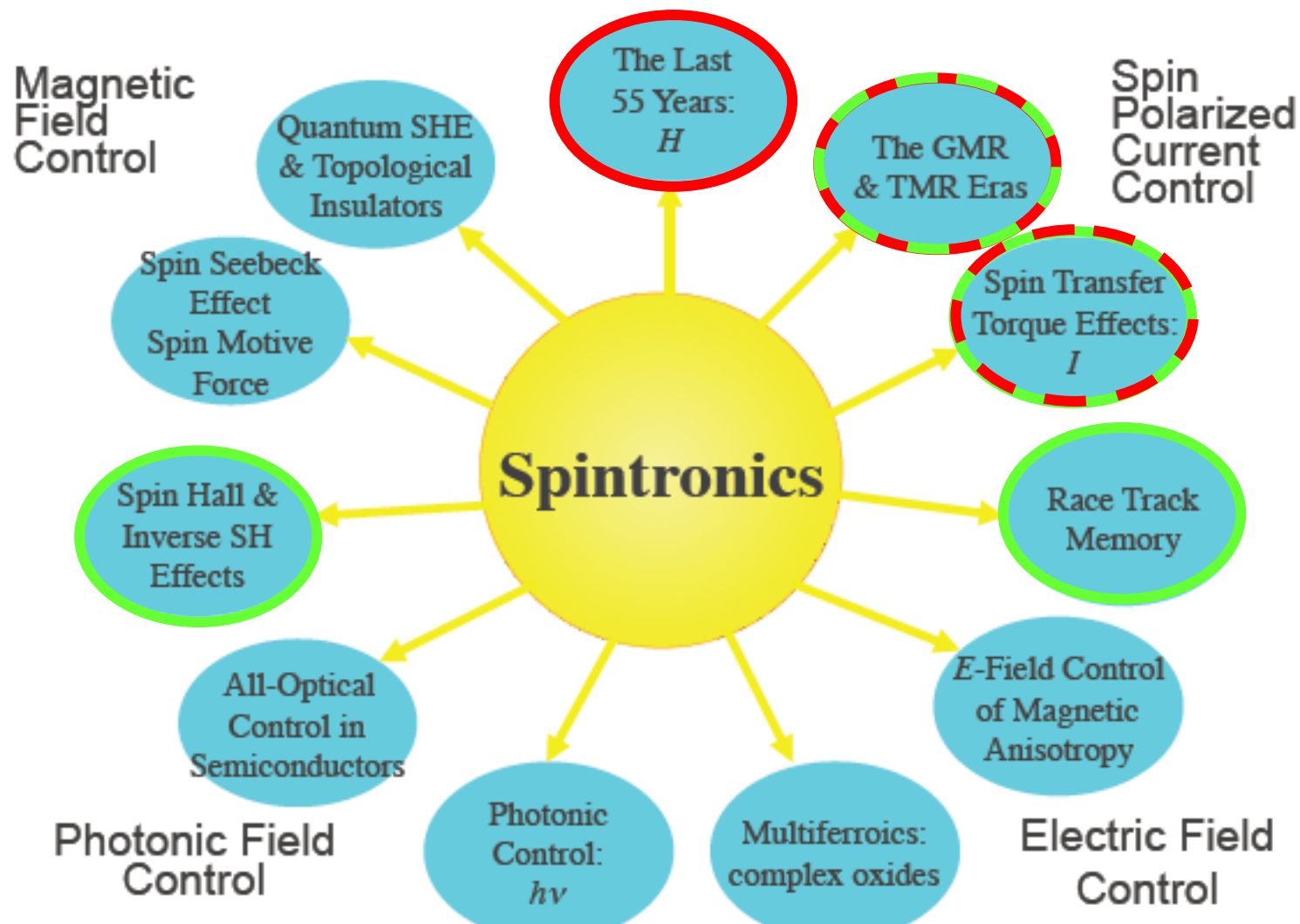


(INTERMEDIATE) CONCLUSION

- Increasing interest for MRAM for stand-alone, embedded memories or “logic-in-memory”
- Spintronics brings non volatility to CMOS circuits for **low-power, normally-off electronics**
- Manufacturing technology mature enough with **pure-play foundries entering the game**
- Design environment “ready-to-use” as **standard library tools**

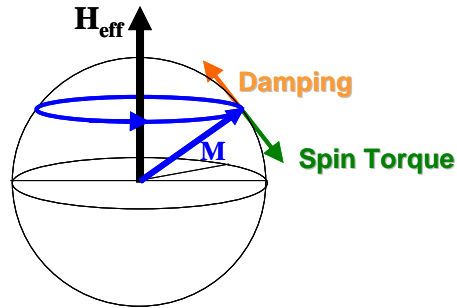


WHAT'S NEXT ?

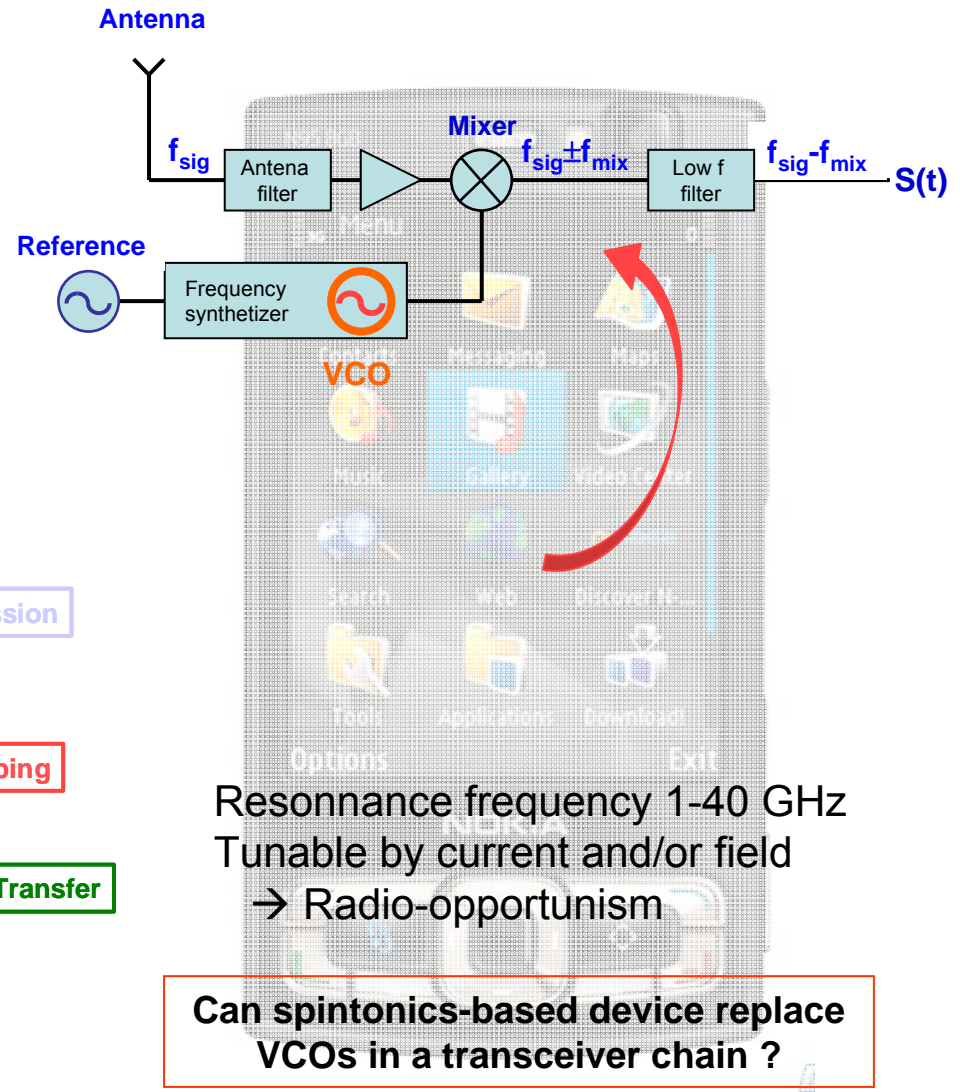


Courtesy Sam Bader

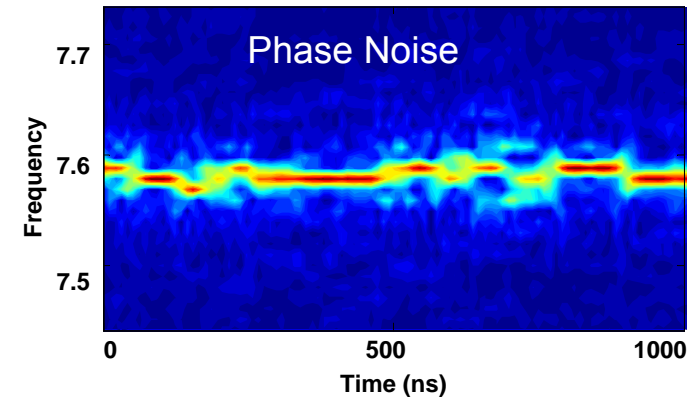
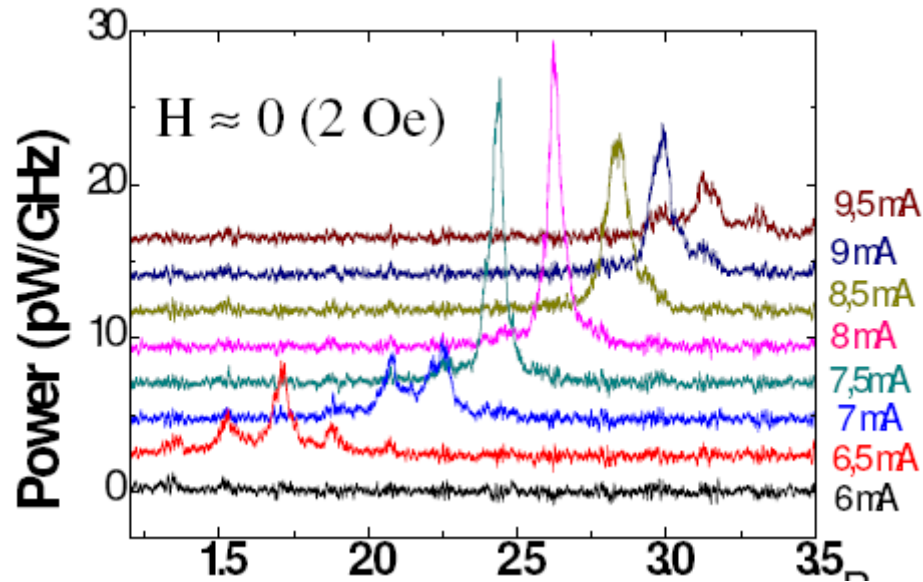
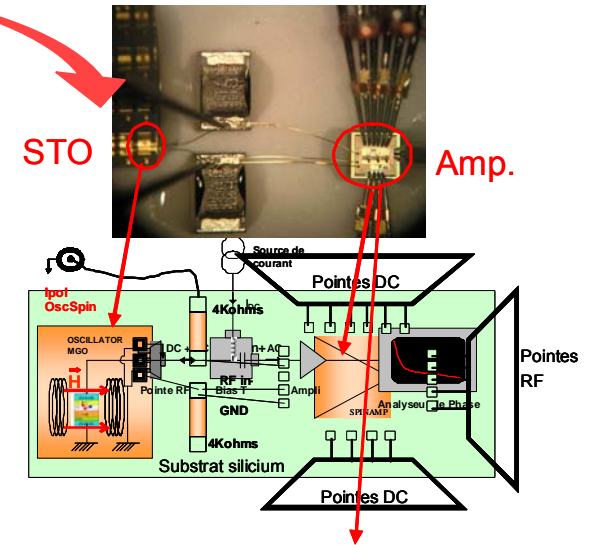
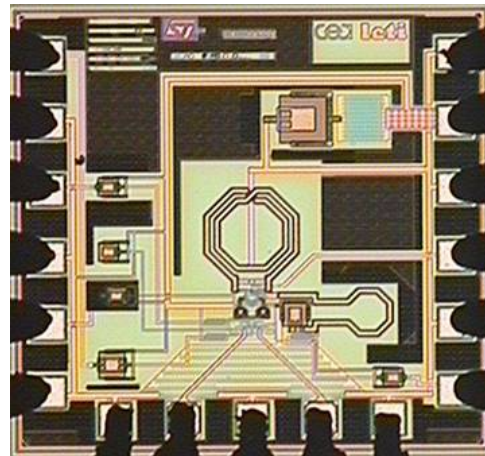
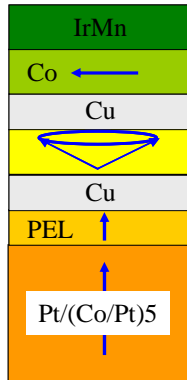
SPIN TRANSFER OSCILLATORS (STO)



If damping = STT \rightarrow Self-sustained precession
 \rightarrow Oscillations of R



SPIN TRANSFER OSCILLATORS (STO)

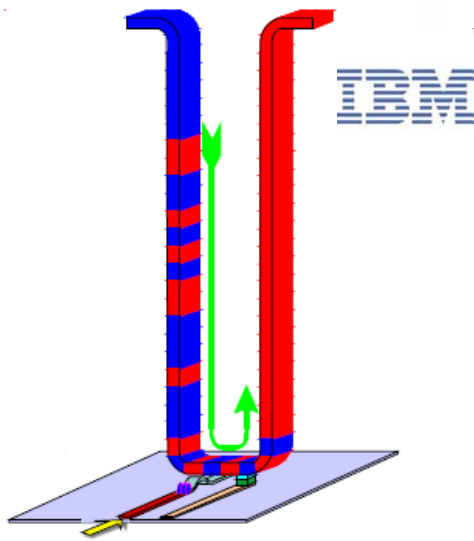


SPIN TRANSFER DOMAIN WALL MOTION

In Domain Wall, local “magnetic” pressure induced by STT → DW motion

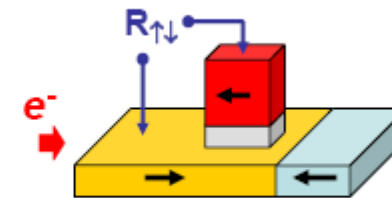
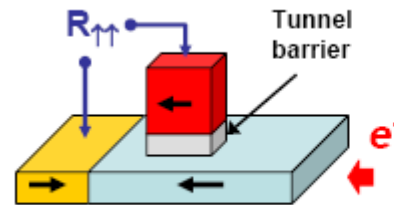


“Race Track Memory”



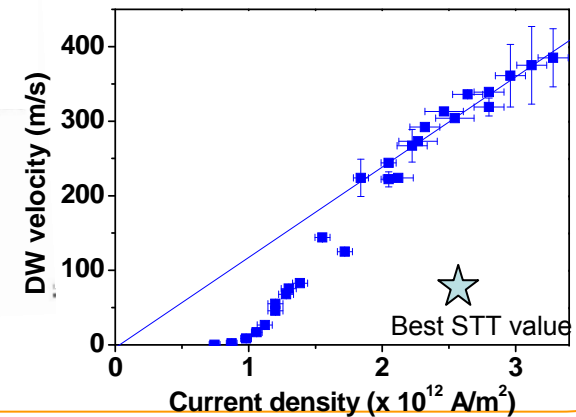
Magnetic shift register

MRAM & logic devices



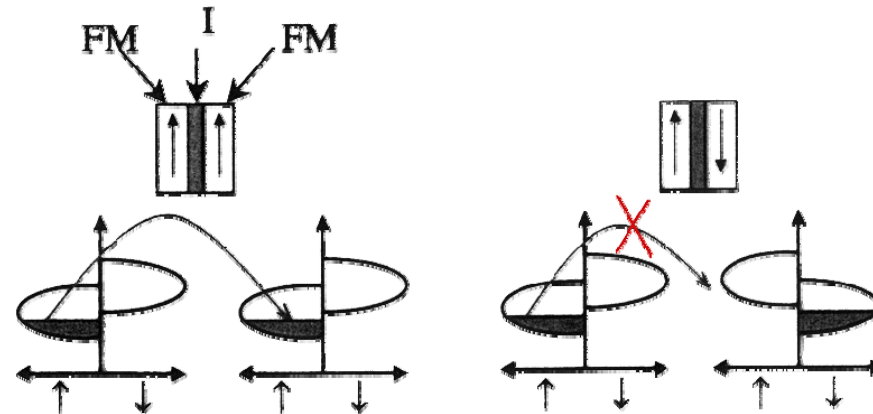
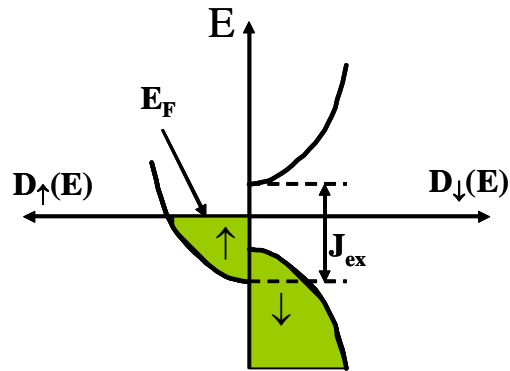
Rashba-induced DW motion in ultra-thin Pt/Co/Al₂O₃ layers

Nature Materials Vol.9, pp.230–234 (2010)



NEW MATERIALS : HEUSLER ALLOYS

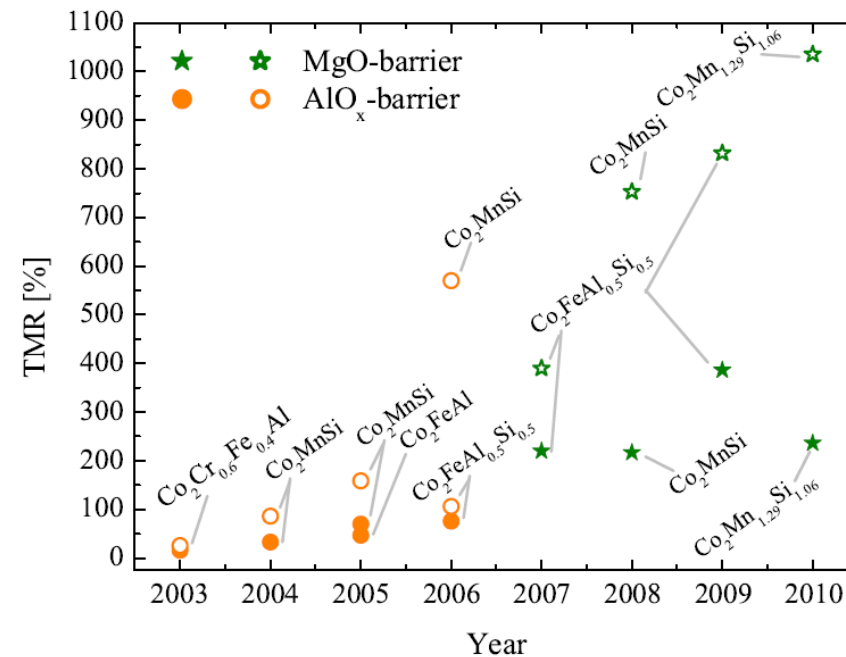
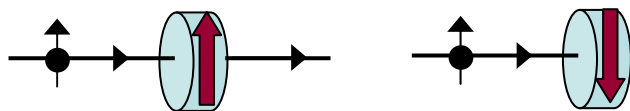
Use « half »-metals (Heusler alloys)



$$TMR = \frac{R_{antipar} - R_{par}}{R_{par}} \rightarrow \infty$$

Integration of half-metals could open the door for spin switches

→ Active logic devices

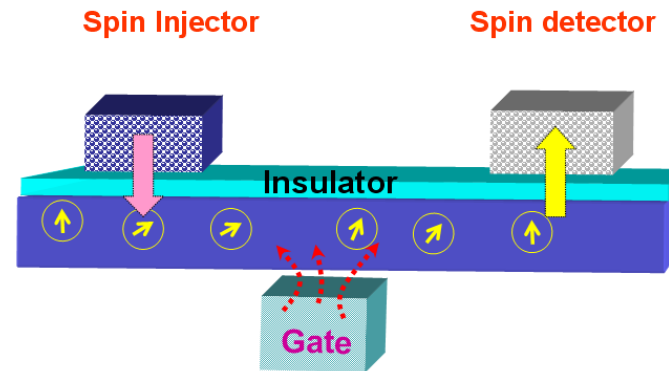
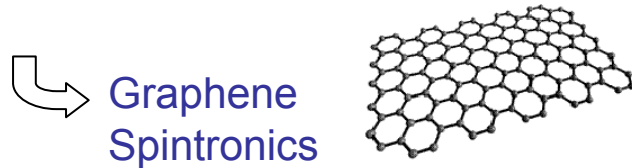


TOWARDS PURE SPIN LOGIC ?

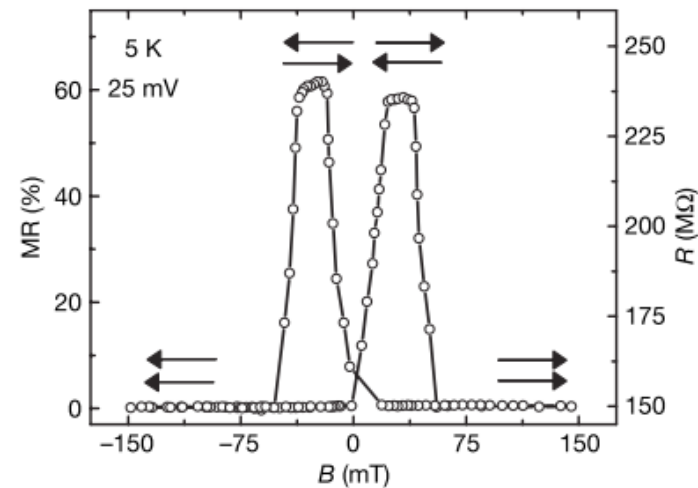
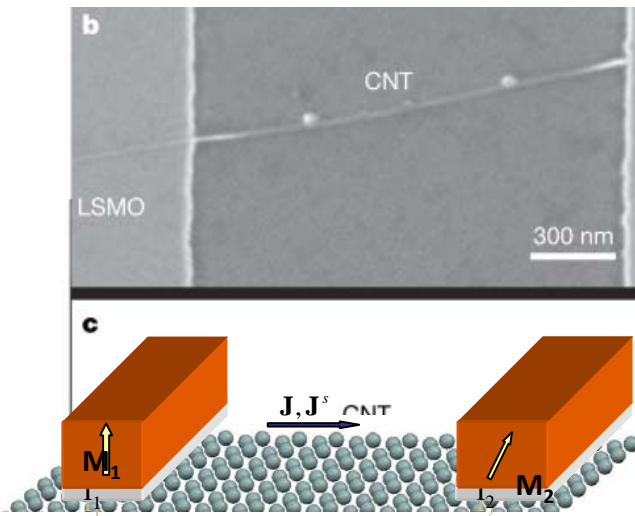
The long quest for a spin transistor ...

Problems:

- No efficient spin injection from FM into SC
- Short spin lifetime in SC
- No magnetic SC at RT



L.Hueso, N.D. Mathur, A.Fert et al, *Nature* **445**, 410, 2007

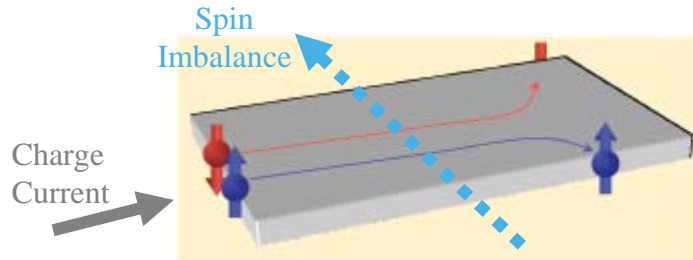


Extremely long lifetime + Efficient spin injection

SPIN-ONLY CURRENTS

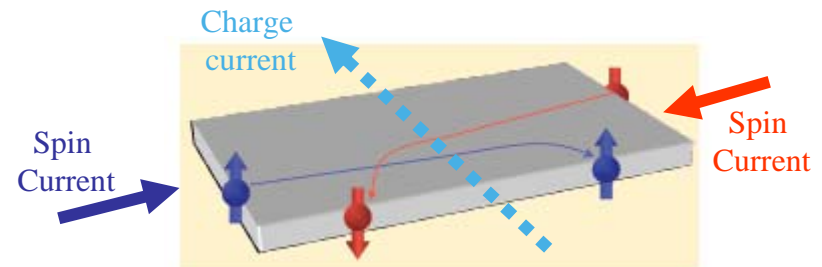
Spin-Hall

Charge current \rightarrow Spin « current »

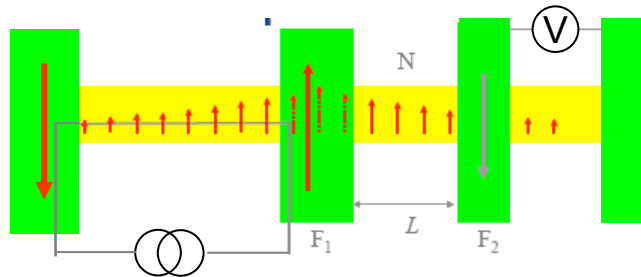


Inverse Spin-Hall

Spin current \rightarrow Charge current

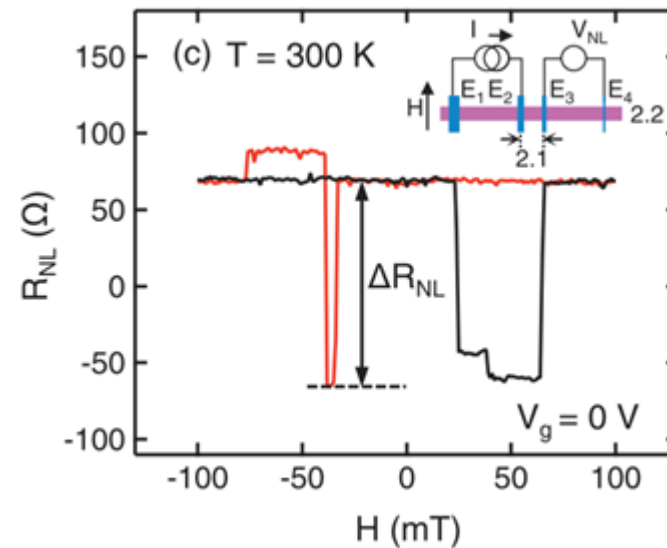


Spin injection into graphene



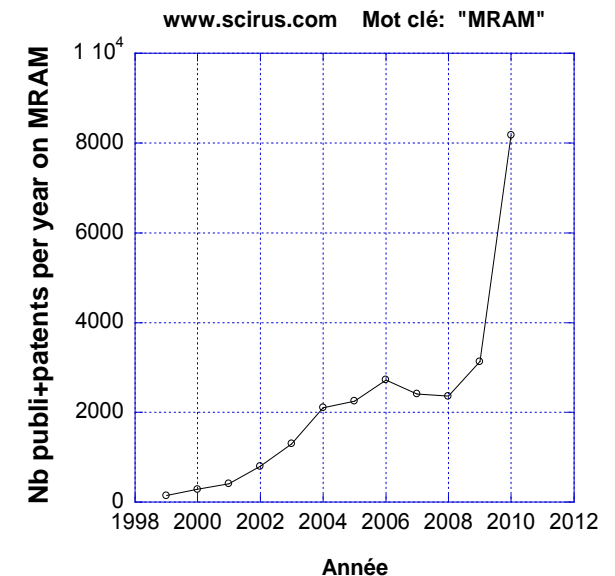
Spin current w/o charge current
Would allow full fonctionnalité with
no heating / power dissipation !

Wei Kan et al (R. K. Kawakami's group), PRL 105, 167202 (2010).
B. Dlubak et al, (A. Fert's group) Appl. Phys. Lett. 97, 092502 (2010)



(FINAL) CONCLUSION

- Increasing interest for MRAM for stand-alone, embedded memories or “logic-in-memory”
- Spintronics brings non volatility to CMOS circuits for **low-power, normally-off electronics**
- Manufacturing technology mature enough with **pure-play foundries entering the game**
- Design environment “ready-to-use” as **standard library tools**
- **Huge development potential**



Important “cultural” gap between magnetics and microelectronics communities

→ Most MRAM players have HDD experience (e.g. magnetics “culture”)

→ “Mutual education” mandatory to move towards adoption of spintronics in VLSI

Do not be afraid of magnetism and magnetic materials ! 😊